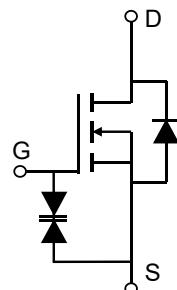


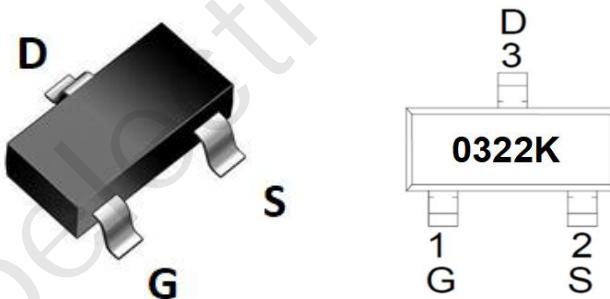
Description

Features

- 30V, 5.8A
- $R_{DS(ON)}$ Typ = 19.3mΩ @ V_{GS} = 4.5V
- $R_{DS(ON)}$ Typ = 25mΩ @ V_{GS} = 2.5V
- $R_{DS(ON)}$ Typ = 51mΩ @ V_{GS} = 1.8V
- Advanced Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead Free
- ESD Protected: 2KV



Schematic Diagram



Marking and Pin Assignment

Package Marking and Ordering Information

Device	Marking	Package	Outline	Reel Size	Reel (pcs)	Per Carton (pcs)
CRMLTU0322K	0322K	SOT-23	TAPING	7"	3000	120000

Absolute Maximum Ratings (@ T_J = 25°C unless otherwise specified)

Symbol	Parameter	Value	Units	
V_{DS}	Drain-to-Source Voltage	30	V	
V_{GS}	Gate-to-Source Voltage	± 10	V	
I_D	Continuous Drain Current	5.8	A	
	$T_A = 100^\circ\text{C}$	3.48	A	
I_{DM}	Pulsed Drain Current ⁽¹⁾	23.2	A	
P_D	Power Dissipation	$T_A = 25^\circ\text{C}$	1.4	W
R_{QJA}	Thermal Resistance, Junction to Ambient ⁽²⁾	89	°C/W	
T_J, T_{STG}	Junction & Storage Temperature Range	-55 to 150	°C	

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 10\text{V}$	-	-	± 10	μA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.4	0.6	0.8	V
		$V_{GS} = 4.5\text{V}, I_D = 3\text{A}$	-	19.3	25	$\text{m}\Omega$
$R_{\text{DS(ON)}}$	Static Drain-Source ON-Resistance ⁽³⁾	$V_{GS} = 2.5\text{V}, I_D = 2\text{A}$	-	25	32.5	$\text{m}\Omega$
		$V_{GS} = 1.8\text{V}, I_D = 1.5\text{A}$	-	51	66	$\text{m}\Omega$
Dynamic Characteristics						
C_{iss}	Input Capacitance		-	620	-	pF
C_{oss}	Output Capacitance	$V_{GS} = 0\text{V}, V_{DS} = 15\text{V}, f = 1\text{MHz}$	-	63	-	pF
C_{rss}	Reverse Transfer Capacitance		-	50	-	pF
Q_g	Total Gate Charge		-	15	-	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0$ to 10V	-	2	-	nC
Q_{gd}	Gate Drain("Miller") Charge	$V_{DS} = 15\text{V}, I_D = 5\text{A}$	-	3	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time		-	6	-	ns
t_r	Turn-On Rise Time	$V_{GS} = 10\text{V}, V_{DD} = 15\text{V}$	-	4	-	ns
$t_{d(off)}$	Turn-Off Delay Time	$I_D = 5\text{A}, R_{\text{GEN}} = 3\Omega$	-	15	-	ns
t_f	Turn-Off Fall Time		-	4.5	-	ns
Drain-Source Diode Characteristics and Max Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current		-	-	5.8	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	23.2	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 3\text{A}$	-	-	1.2	V

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

2. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB

3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.

Test Circuit

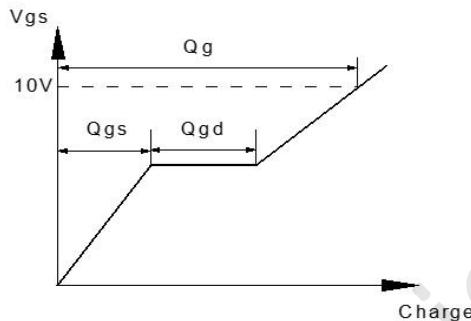
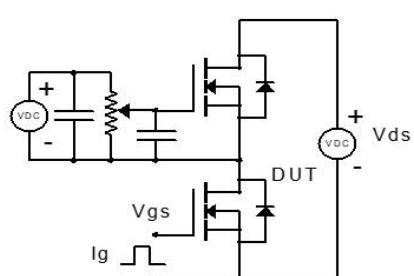


Figure 1: Gate Charge Test Circuit & Waveform

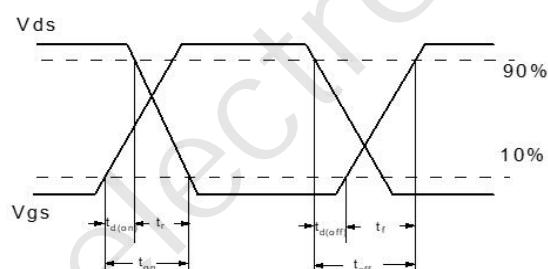
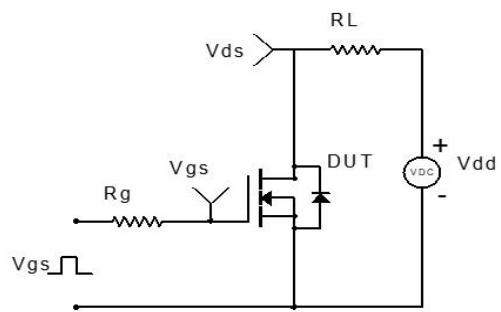


Figure 2: Resistive Switching Test Circuit & Waveform

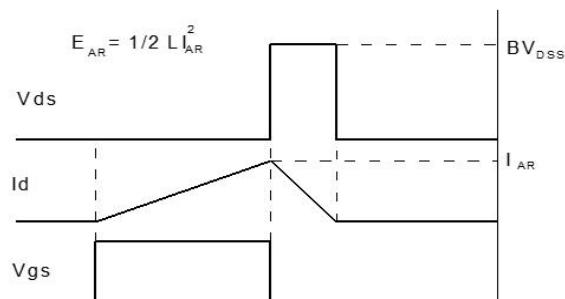
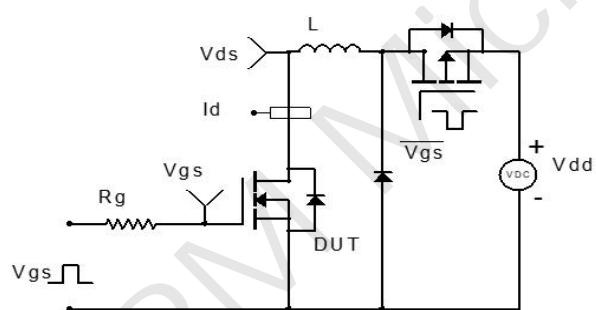


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

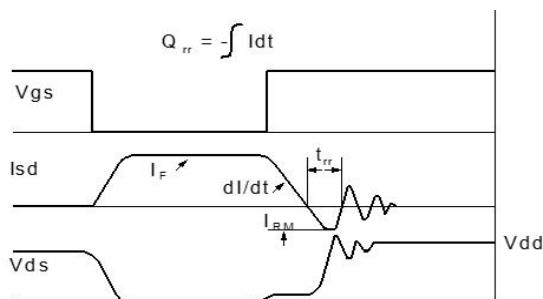
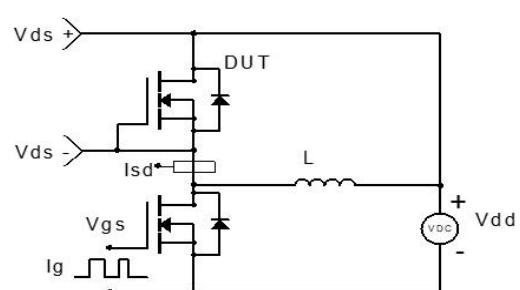
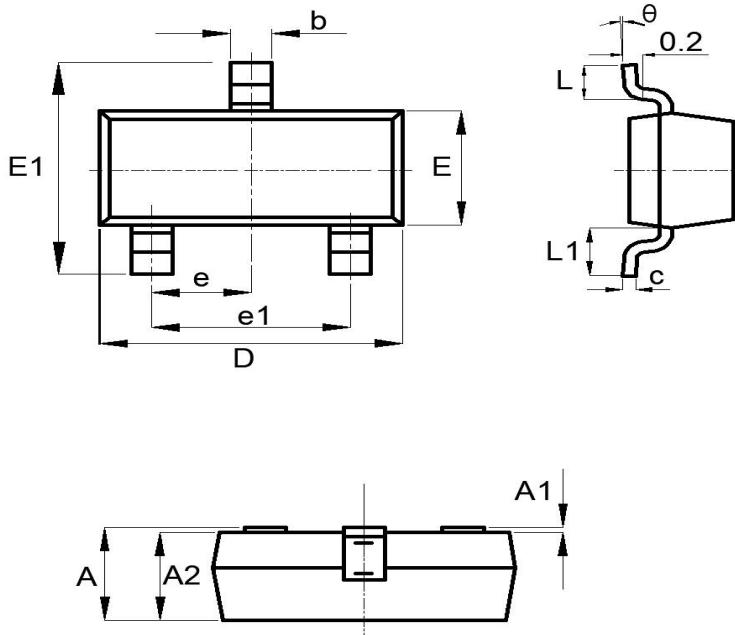


Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(SOT-23)



SOT-23			
SYMBOL	MIN	TYP	MAX
A	0.90	-	1.15
A1	0.01	-	0.15
A2	0.90	-	1.05
b	0.30	-	0.50
c	0.08	-	0.15
D	2.80	-	3.00
E	1.20	-	1.40
E1	2.25	-	2.55
e	-	0.95	-
e1	1.80	-	2.00
L	0.30	0.40	0.50
L1	0.50	0.55	0.60
θ	0°	-	8°

UNIT(mm)

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